

Application/Control No.	Applicant(s)/Patent und Reexamination	ier
10/785,039	HUANG, YAO-CHUNG	3
Examiner	Art Unit	
Chuck Mah	3677	

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Class	Subclass	Date	Examiner
16	428		
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403	12/-122		
482	126-12	, ·	
123	185.2		
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

(INCLUDING SEARCH	TES STRATEGY	<b>'</b> )
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